

Notice of References Cited

Application/Control No.

10/043,791

Applicant(s)/Patent Under
Reexamination
ASSARABOWSKI ET AL.

Examiner

Dah-Wei D. Yuan

Art Unit

1745

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,294,149	09-2001	Autenrieth et al.	423/648.1
	B	US-6,489,052	12-2002	Acker, William P.	429/40
	C	US-2002/0058165	05-2002	Gebhardt et al.	429/13
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 59-152210	08-1984	Japan	Tomomura et al.	C01B 23/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.